

Abstract

2 A novel two-stage clamp used in testing a device-under-test (DUT) is
herein presented. The two-stage clamp provides two sequential actuations
4 via one linear force, and includes clamps moving in multiple different
directions. The two-stage clamp uniquely uses the DUT being clamped to
6 provide the linkage and timing for the two-stage actuation of clamps moving
in three different directions.